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SUBMISSION TYPE:	NEW ASSIGNMENT
NATURE OF CONVEYANCE:	ASSIGNMENT

CONVEYING PARTY DATA

Name	Execution Date
Michael F. Steiber	03/26/2007
Dale E. Schafernak	03/10/2007
Peggie A. Bolan	03/26/2007

RECEIVING PARTY DATA

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Street Address:	500 West Monroe Street	
Internal Address:	Suite 2010	
City:	Chicago	
State/Country:	ILLINOIS	
Postal Code:	60661	

PROPERTY NUMBERS Total: 1

Property Type	Number
Application Number:	29306505

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NAME OF SUBMITTER: John S. Paniaguas

Total Attachments: 1

PATENT REEL: 020788 FRAME: 0042

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PATENT REEL: 020788 FRAME: 0043

Abstract of the Disclosure

[00118] A method of semiconductor manufacturing is disclosed in which doping is accomplished by the implantation of ion beams formed from ionized molecules, and more particularly to a method in which molecular and cluster dopant ions are implanted into a substrate with and without a co-implant of non-dopant cluster ion, such as a carbon cluster ion, wherein the dopant ion is implanted into the amorphous layer created by the co-implant in order to reduce defects in the crystalline structure, thus reducing the leakage current and improving performance of the semiconductor junctions. Dopant ion compounds of the form $A_nH_x^+$ and $A_nR_zH_x^+$ are used in order to minimize crystal defects as a result of ion implantation. These compounds include co-implants of carbon clusters with implants of monomer or cluster dopants or simply implanting cluster dopants. In particular, the invention described herein consists of a method of implanting semiconductor wafers implanting semiconductor wafers with carbon clusters followed by implants of boron, phosphorus, or arsenic, or followed with implants of dopant clusters of boron, phosphorus, or arsenic. The molecular cluster ions have the chemical form $A_n H_x^{\dagger}$ or $A_n R_z H_x^{\dagger}$ where A designates the dopant or the carbon atoms, n and x are integers with n greater than or equal to 4, and x greater than or equal to 0, and R is a molecule which contains atoms which, when implanted, are not injurious to the implantation process (for example, Si, Ge, F, H or C). These ions are produced from chemical compounds of the form A_bL_zH_m, where the chemical formula of Lz contains R, and b may be a different integer from n and m may be an integer different from x and z is an integer greater than or equal to zero...

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